

Search Notes



Application/Control No.

10/817,196

Examiner

David Q. Nguyen

Applicant(s)/Patent under
Reexamination

JAIN ET AL.

Art Unit

2681

SEARCHED

Class	Subclass	Date	Examiner
455	411	10/14/05	DN
370	332		
455	435.1		
340	5.21		
340	5.24		
380	242		
380	220	10/14/05	DN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East search	10/14/05	DN
Search note	10/14/05	DN